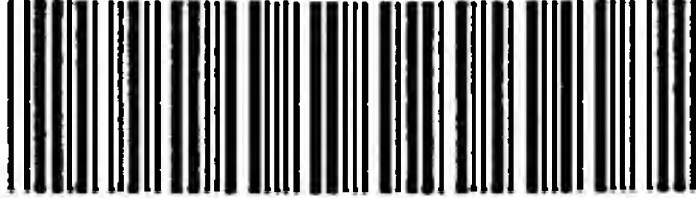


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/604,555	AUDET ET AL.	
	Examiner	Art Unit	
	Hae M. Hyeon	2839	

SEARCHED			
Class	Subclass	Date	Examiner
439	66	2/05	hnh
439	78	↓	↓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
361/760 and 439/876 Text Searched	2/05	hnh